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Depositor: KAREN CINO-MARS

Signature &

IN THE UNITED STATES PATENT AND TRADEMARK_OFFICE

<u>In re application of</u>

Mitsuru Uda, et al.

8/20/03 Group Art Unit:

Serial No. 10/045,377

Examiner:

11/09/01 Filed:

International Business Machines Corporation

2070 Route 52

Hopewell Junction, NY 12533

TITLE: METHOD AND APPARATUS FOR INSPECTING RESIST PATTERN

INFORMATION DISCLOSURE STATEMENT

Assistant Commissioner for Patents Alexandria, VA 22313-1450

Sir:

Pursuant to the duty of disclosure set forth in 37 C.F.R. 1.56, and further pursuant to the provisions of 37 C.F.R. 1.97 and 1.98, applicants hereby respectfully submit copies of the prior patents and publications as listed on Form PTO-1449, attached hereto.

In citing these documents, no representation is made nor intended as to the pertinency or non-pertinency of the art, that better art than that listed is not available, or that other art is not applicable.

> Respectfully submitted, Mitsuru Uda, et al.

James /J. Ciof /i,

Registration No.51,564

Telephone No. 845-894-3363

DEFORMATION DISCLOSURE CITATION (Use Several sheets if necessary)					Docket Number (Optional) JP920000352US1		Application Number 10/045,377		
					Applicant(s) MITSURU UDA, ET AL.				
					Filing Date	Group Art Unit			
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